

Search Notes

Application/Control No.

10/537,794

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

DONG ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	65.4	6/16/2007	HP
	65.6		
	65.2		
	65.3		
903	914	6/16/2007	HP
	922		
	923		
701	22	6/16/2007	HP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR